

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Sergey A. Velichko et al.	Examiner: Craig Steven Miller
Serial No.:	09/834,751	Group Art Unit: 2857
Filed:	April 13, 2001	Docket No.: 303.750US1
Title:	CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING	

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.111

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

This paper responds to the Office Action mailed on January 26, 2006. Please amend the above-identified patent application as follows.